

FCC ID:2ALPG-FT3

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$[(\text{max. power of channel, including tune-up tolerance, mW}) / (\text{min. test separation distance, mm})] \cdot \sqrt{f(\text{GHz})} \leq 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- $f(\text{GHz})$ is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

BT:

Modulation	Channel Freq. (GHz)	Conduct ed power (dBm)	Conducte d power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
GFSK	2.402	2.92	1.96	2±1	3.00	2.00	<5	0.61847	3.00	YES
	2.441	2.76	1.89	2±1	3.00	2.00	<5	0.62347	3.00	YES
	2.480	1.71	1.48	2±1	3.00	2.00	<5	0.62843	3.00	YES
π/4-DQPSK	2.402	3.15	2.07	2.5±1	3.50	2.24	<5	0.69393	3.00	YES
	2.441	2.94	1.97	2.5±1	3.50	2.24	<5	0.69954	3.00	YES
	2.480	2.07	1.61	2.5±1	3.50	2.24	<5	0.70511	3.00	YES
8DPSK	2.402	3.08	2.03	2.5±1	3.50	2.24	<5	0.69393	3.00	YES
	2.441	3.04	2.01	2.5±1	3.50	2.24	<5	0.69954	3.00	YES
	2.480	1.99	1.58	2.5±1	3.50	2.24	<5	0.70511	3.00	YES

simultaneous emission

Power density Limits BT	Calculate Evaluation result	Power density Limits
0.70511	0.70511	3

Conclusion:

For the max result : $0.70511\text{W/Kg} \leq 3.0$ for 1g SAR, No SAR is required.

Jason chen

Signature:

Date: 2017-4-13

NAME AND TITLE (Please print or type): Jason Chen /Manager

COMPANY (Please print or type): Shenzhen NTEK Testing Technology Co., Ltd./ 1/F, Building E, Fenda Science Park, Sanwei Community, Xixiang Street Bao'an District, Shenzhen P.R. China.